

Receipt date: 07/25/2006

10/586953

10586953 - GAU: 1792

10/586953 Rec'd PCT/PTO 25 JUL 2006

Form PTO-1449 (REV. 1/06)		US Dept. of Commerce <b>PATENT &amp; TRADEMARK OFFICE</b>		ATTY DOCKET NO. 128832		New U.S. National Phase of PCT/JP2005/000839	
INFORMATION DISCLOSURE STATEMENT  (Use several sheets if necessary)				APPLICANTS Makoto IIDA et al.  FILING DATE July 25, 2006			
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Examiner Initials	Cite No.	Document Number	Date	Name			
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EXAMINER				/G. Nagesh Rao/ (10/22/2009)		DATE CONSIDERED 10/22/2009	
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ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /G.N.R.